

Depletion-Mode Power MOSFET

General Features

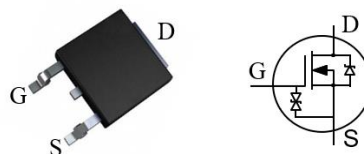
- Depletion Mode (Normally On)
- Proprietary Advanced Planar Technology
- Rugged Polysilicon Gate Cell Structure
- RoHS Compliant
- Halogen-free Available

BV_{DSX}	R_{DS(ON)(Max.)}	I_D
450V	2Ω	3.75A

TO-252

Applications

- Transient Protect
- Start-up
- Converters
- Normally On Switches
- LED Drive Circuits
- Power Supplies
- Current Source
- Voltage Source



Ordering Information

Part Number	Package	Marking	Remark
DMD4523E	TO-252	4523E	Halogen Free

Absolute Maximum Ratings

 $T_A=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	DMD4523E	Unit
V _{DSX}	Drain-to-Source Voltage ^[1]	450	V
V _{DGX}	Drain-to-Gate Voltage ^[1]	450	V
I _D	Continuous Drain Current	3.75	A
I _{DM}	Pulsed Drain Current ^[2]	15	
P _D	Power Dissipation	36	W
V _{GS}	Gate-to-Source Voltage	±20	V
V _{ESD}	Gate Source ESD ^[3]	3000	V
	Source to Gate ESD ^[3]	3000	V
T _L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	°C
T _J and T _{STG}	Operating and Storage Temperature Range	-55 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	DMD4523E	Unit
R _{θJC}	Thermal Resistance, Junction-to-Case	3.47	°C/W

Electrical Characteristics

OFF Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSX}	Drain-to-Source Breakdown Voltage	450	--	--	V	$V_{GS} = -10\text{V}$, $I_D = 250\mu\text{A}$
$I_{DS(OFF)}$	Drain-to-Source Leakage Current	--	--	1	μA	$V_{DS} = 450\text{V}$, $V_{GS} = -10\text{V}$
I_{GSS}	Gate-to-Source Leakage Current	--	--	20	μA	$V_{GS} = +20\text{V}$, $V_{DS} = 0\text{V}$
		--	--	-20		$V_{GS} = -20\text{V}$, $V_{DS} = 0\text{V}$

ON Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	--	2	Ω	$V_{GS} = 0\text{V}$, $I_D = 1\text{A}^{[4]}$
$V_{GS(OFF)}$	Gate-to-Source Cut-off Voltage	-1.7	--	-4.0	V	$V_{DS} = 3\text{V}$, $I_D = 8\mu\text{A}$
gfs	Forward Transconductance	--	3100	--	mS	$V_{DS} = 5\text{V}$, $I_D = 1\text{A}^{[4]}$

Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
C_{ISS}	Input Capacitance	--	1.11	--	nF	$V_{GS} = -7\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$
C_{OSS}	Output Capacitance	--	62.80	--	pF	
C_{RSS}	Reverse Transfer Capacitance	--	6.54	--		
Q_G	Total Gate Charge	--	158.82	--	nC	$V_{GS} = -6\text{V} \sim 0\text{V}$ $V_{DD} = 25\text{V}$ $I_D = 200\text{mA}$
Q_{GS}	Gate-to-Source Charge	--	58.26	--		
Q_{GD}	Gate-to-Drain (Miller) Charge	--	50.55	--		

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(on)}$	Turn-on Delay Time	--	5.71	--	ns	$V_{GS} = -6\text{V} \sim 0\text{V}$ $V_{DD} = 25\text{V}$ $I_D = 200\text{mA}$ $R_G = 10\Omega$
t_{rise}	Rise Time	--	18.45	--		
$t_{d(off)}$	Turn-off Delay Time	--	26.40	--		
t_{fall}	Fall Time	--	18.46	--		

Source-Drain Diode Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V_{SD}	Diode Forward Voltage	--	0.8	1.5	V	$I_{SD} = 200\text{mA}^{[4]}$, $V_{GS} = -10\text{V}$

NOTE:

[1] $T_J = +25^\circ\text{C}$ to $+150^\circ\text{C}$

[2] Repetitive rating, pulse width limited by maximum junction temperature.

[3] The test is based on JEDEC EIA/JESD22-A114(HBM).

[4] Pulse width $\leq 380\mu\text{s}$; duty cycle $\leq 2\%$.

Typical Characteristics

Figure 1. Maximum Power Dissipation vs. Case Temperature

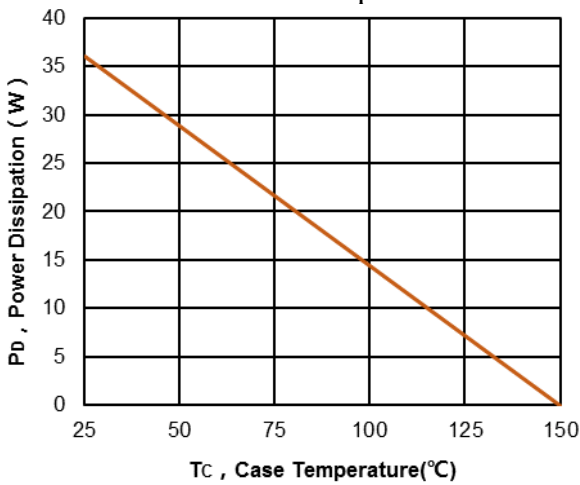


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

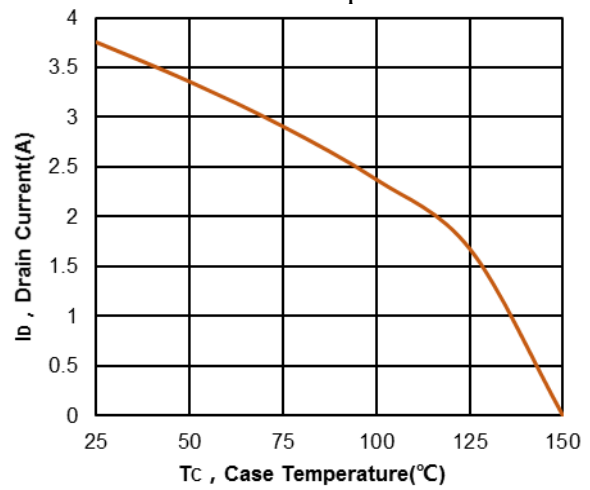


Figure 3. Typical Output Characteristics

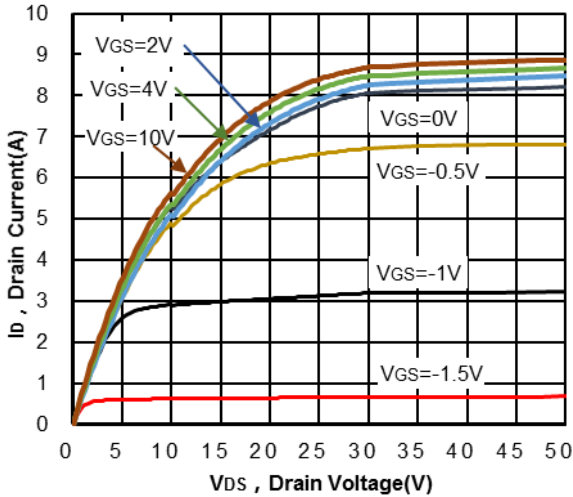


Figure 4. Typical Transfer Characteristics

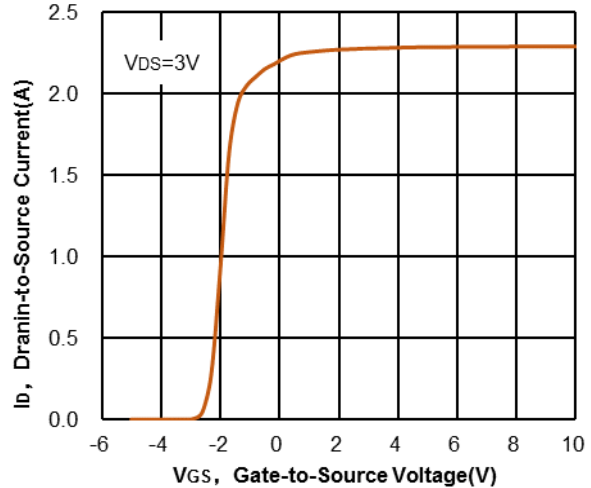


Figure 5. Typical Capacitance vs. Drain-to-Source Voltage

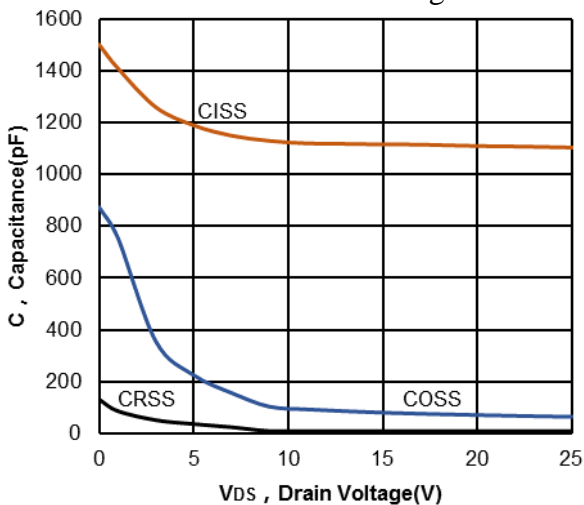
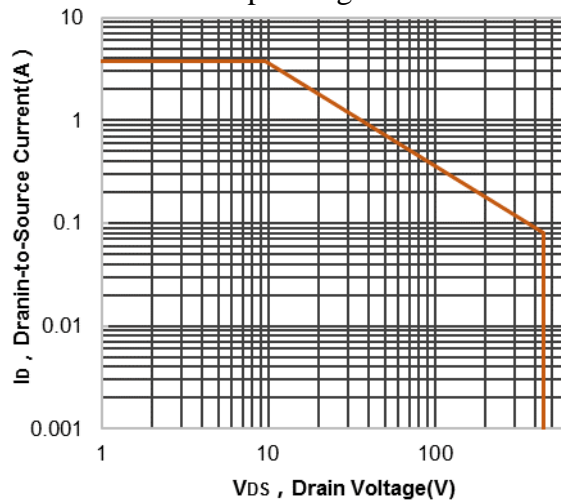


Figure 6. Maximum Rated Safe Operating Area



Typical Application

In circuits of capacitive loads, instruments, and communication equipment, using DMD4523E can effectively suppress transient surges and provide overcurrent protection. As shown in Figure 7, In the circuit, only one depletion mode MOSFET and a resistor are used to limit the magnitude of the current flowing through the load and provide overcurrent protection. The application of DMD4523E has the characteristics of fast response speed, simple circuit structure and low cost.

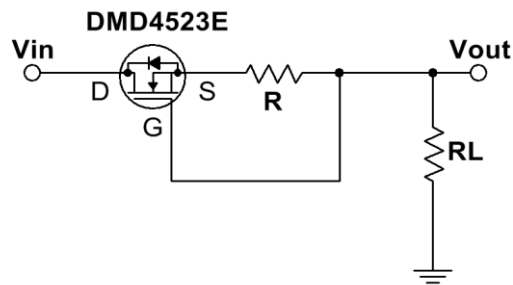


Figure 7. The DMD4523E is used for current limiting

In Figure 8, by selecting an appropriate Zener diode VD1, a stable output voltage Vout can be obtained. The DMD4523E can work under higher voltage, it can provide overvoltage protection and transient surge suppression for the load.

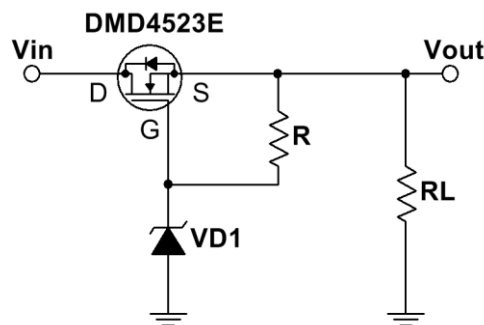
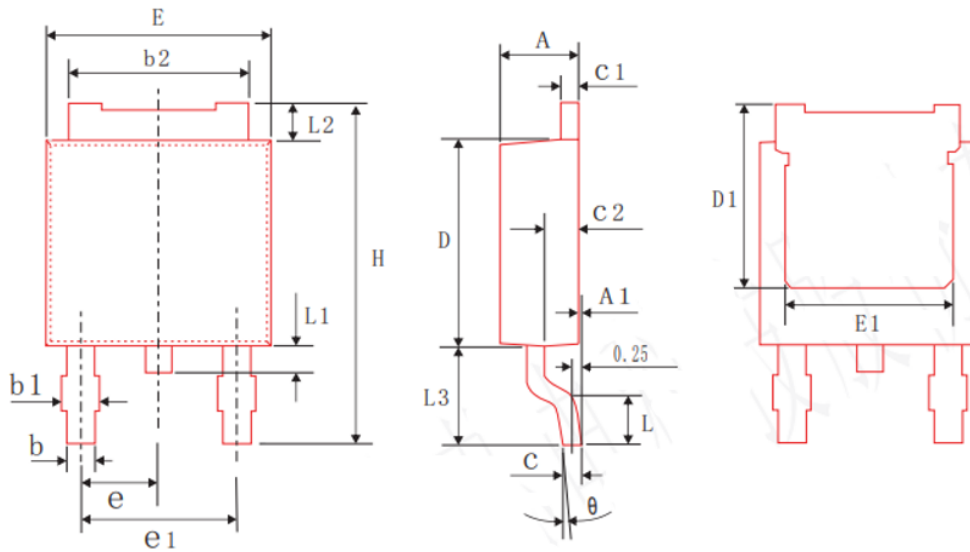


Figure 8. The DMD4523E for overcurrent and overvoltage protection

Package Dimensions
TO-252


SYMBOL	MIN	NOM	MAX
A	2.2	2.3	2.4
A1	0.00	0.05	0.10
b	0.762	0.812	0.862
b1	--	--	1.10
b2	5.23	5.33	5.43
c	0.458	1.508	0.558
c1	0.458	0.508	0.558
c2	0.80	1.00	1.20
D	6.00	6.10	6.20
D1	5.25	5.45	5.65
H	10.00	10.10	10.20
E	6.50	6.60	6.70
E1	4.75	4.85	4.95
e1	4.37	4.57	4.77
L	--	--	1.45
L1	0.60	0.75	0.90
L2	0.90	1.10	1.30
L3	2.80	3.00	3.20
θ	0°	4°	8°
e	2.285 BSC		

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